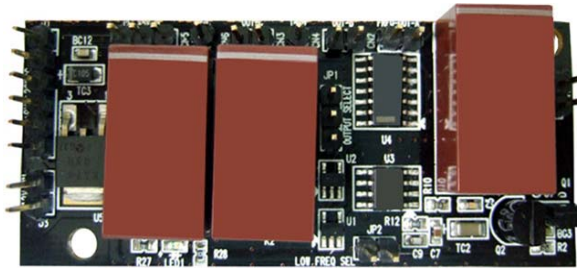


**Applications**

- **X-TAL/OSC Device Testing (Support 3Pins)**
- **Small Signal Amplifier (Up to 100Mhz)**
- **High Frequency Measurements (3Channels)**

**Special Features**

- **Designed For High frequency range (1KHZ - 100Mhz)**
- **Provide output selection pins (Real / Divide)**
- **Completely check for 32.768Khz Low frequency**
- **Included 1/4 divider logic. (100Mhz => 25Mhz)**
- **Provide Control pin for guarding frequency oscillation**
- **Directly connected for 2 pins of X-TAL**
- **Additional connectable 3 pins interface**
- **Build-in Pre-Amplified Logic**
- **Wide Power Sources (+5V. +9V ~ +25V)**

Descriptions

This product was developed special design for dedicated X-TAL or High Frequency Device Measuring. Almost, all ICT users have common difficulties in testing X-TAL devices or High frequency measuring. The reason is intrinsic capacitance which is existing inside the test system and affects the test procedure. This is especially true in the 1MHz and under range where this kind of interference is critical. (Example: 32.768KHz RTC: Real Time Clock)

In order to troubleshoot this symptom, there should be two key factors that need to be considered.

One is isolating the intrinsic capacitance source from the target X-TAL device, the other is to amplify the extremely small X-TAL output frequency. XTALOSpro solved these two issues effectively.

The first, internal capacitance shielding under -80 dB can be achieved thru two RF relay at each X-TAL lead.

To increase input impedance, high impedance RF FET devices are used.

The second, to keep flat linear amplification characteristics, ultra high frequency logic and adequate impedance matching circuitry were specially designed.

Finally, X-TALOSpro does not need any extra test source and operates immediately after power on.

The user can control relay operation with ease during the power test.

If you would like know more detailed information, please access the Testing House website. (www.testinghouse.com)

Specification

- * **Input Frequency Range:** 1KHz ~ 100MHz
 - * **Built-In Divide Function:** 1 ÷ 4
 - * **Input Impedance:** 1MOhms / Under 10pF
 - * **Minimum Input Sensitivity:** -10dBm (@100Mhz) / 0dBm (@120Mhz)
 - * **Isolation Signal Level:** Min. -60dBm (@100Mhz)
 - * **Support Channels:** 3Channels
 - * **Operating DC Power Sources:** (Dual Power) +9V ~ +25V / 4.75V ~ +5.25V
 - * **DC Power Current:** 150mA (@12V) / 125mA (@5V)
 - * **Board Size:** 700mm (w) x 30mm(v) x 15mm(H)
- ***Output Impedance:** 50Ohms

In keeping with TH's policy of providing continuing improvements, specifications are subject to change

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